

<b>Search Notes</b>  <b>*1059076</b> <b>8*</b>	<b>Application/Control No.</b> 10590768	<b>Applicant(s)/Patent Under Reexamination</b> JENSEN ET AL.
	<b>Examiner</b> Young J Kim	<b>Art Unit</b> 1637

<b>SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

<b>SEARCH NOTES</b>			
<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>	
Patent Databases (USPT, USPPG, EPO, JP0, DERWENT, IBM-TDB) - see enclosed for text search strategy	8/6/2009	/YJK/	
Updated	12/8/2010	/YJK/	

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
	Interference search history - see enclosed for strategy	12/8/2010	/YJK/

	/Young J Kim/ Primary Examiner.Art Unit 1637
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